



Yield-Man is an enterprise yield management solution that offers unattended monitoring, scheduled reporting, real-time alerts and is approaching petabytes managed worldwide! It ensures production stays within the expected yield parameters and equips engineers with the tools for detailed analysis should anomalies arise.

It streamlines production test yield management by automating data collection and analysis processes. Yield-Man effectively acts like a silent sentry, monitoring yield for all device types across different subcons enabling management by exception. With flexible, scheduled report generation and email alerting, Yield-Man frees up time to focus on strategic initiatives.

Yield-Man employs a relational database to act as a central repository for test data, enabling long term trend analysis, correlations across multiple test flows (temperatures, fab, wafer sort, final test, etc.) and fast report generation even for huge datasets. The database also facilitates deep, multi-variable characterization reducing the total characterization time from 6 months to only 6 hours!

Even with all this power, Galaxy's software is intuitive, easy to use, and since Examiner-Pro acts as a common user interface for all Galaxy products, growing into Yield-Man requires no special training.

Yield-Man is a scalable solution whether at a pre-revenue startup with one engineer, a global company with thousands of them, or anywhere in between. For those with smaller volumes who need the power of the relational database but may not currently need the automation engine of the full Yield-Man solution, ask us about Yield-Man Lite!

For more than 25 years Galaxy Semiconductor is the trusted solution for enhancing yields, reducing defects per million (DPM), and optimizing semiconductor manufacturing processes. Galaxy's experienced team provides powerful, scalable, and easy to use intelligent data analytics while providing first class support.

FEATURES AND BENEFITS

- **AUTOMATED DATA RETRIEVAL, VALIDATION & INSERTION:** Collects production data from anywhere in the world, validates it against user-defined criteria, and then automatically inserts it into a MariaDB database. Processes all popular test data formats, including STDF, GDF, WAT, PCM, compressed files and over 120 more formats.
- **PROGRAMMABLE YIELD & TEST ALARMS:** A flexible interface lets you define yield monitoring rules that check for low yield conditions on any individual bin or combination of bins, or on specific parametric test results.
- **AUTOMATED ACCURATE & CONSOLIDATION OF TEST RE-TEST DATA:** Automatically consolidates test and retest data to provide an accurate yield assessment and avoid false alarms.
- **MANAGEMENT WEB-BASED DASHBOARDS:** With interactive Web-based Semiconductor Intelligence Dashboards, operations and business unit executives can have near real-time access to yield, throughput, cost and other key performance indicators (KPIs) from any Web browser.
- **DIE TRACE:** Correlates final test issues to geographical and wafer-specific issues. Interactive drill-down from final test data to exact (x,y) die locations
- **FAB CORRELATION GENEALOGY REPORTS:** Correlates probe test yield with fab parameters, providing lot traceability across the supply chain
- **INTERACTIVE DRILL-DOWN DATA ANALYSIS:** With Examiner-Pro's™ interactive mode, zoom into histograms, trends, scatter plots and wafer maps to examine and compare specific tests for in-depth root cause analysis
- **DEEP MULTI-VARIABLE CHARACTERIZATION:** Reduces total characterization time from 6 months to 6 hours! Flexible, custom variable naming and hierarchy setting allowing for customized reports.